ELECTRICAL TEST PROBE

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Assignee: Tektronix, Inc., Wilsonville, Oreg.

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Field of Search ......................... D10/80, 103, 46; 29/844, 847, 862, 174/89, 750; 324/72.5, 156; 149, 158 P; 439/482, 585, 374, 824, 819

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CLAIM

The ornamental design for an electrical test probe, as shown.

DESCRIPTION

FIG. 1 is a perspective view of an electrical test probe showing our new design;
FIG. 2 is a left side elevational view thereof, the right side elevational view being a mirror image;
FIG. 3 is a top plan view thereof;
FIG. 4 is a bottom plan view thereof;
FIG. 5 is a front elevational view thereof; and,
FIG. 6 is a rear elevational view thereof.